

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/668,206	SHIN ET AL.	
Examiner	Art Unit	
Thuy V. Tran	2821	

SEARCHED				
Class	Subclass	Date	Examiner	
315	160-161	11/9/2004	T.T.	
-	164	11/9/2004	-	
-	169.1	11/9/2004		
. <b>-</b>	. 169.3	11/9/2004	-	
345	204-205	11/9/2004	-	
-	211	11/9/2004	-	
-	76	11/9/2004	-	
-	82	11/9/2004	-	
-	84	11/9/2004		
	updated	2/24/2005	T.T.	
315	169.2	2/24/2005	T.T.	

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
315	169.2	2/24/2005	т.т.		
315	169.3	2/24/2005	-		
345	76	2/24/2005	-		

SEARCH N (INCLUDING SEAR)		·)
	DATE	EXMR
EAST Text Search	11/9/2004	т.т.
Updated EAST Text Search	2/24/2005	т.т.
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